

Search Notes



Application/Control No.

10/530,271

Examiner

Matthew C. Landau

Applicant(s)/Patent under
Reexamination

YOSHIHARA ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	543.004, 295	11/17/07	M
365	158, 171, 173, 209		
360	324.2		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EWST Search (printout included)	11/17/07	M